



# Optical modeling and simulation of thin-film Cu(In,Ga)Se<sub>2</sub> solar cells

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# Outline

- **Introduction**
- **Optical modeling of thin-film solar cells**
- **Optical simulator SunShine**
- **Results**
  - Optical simulation of thin Cu(In,Ga)Se<sub>2</sub> solar cells
- **Conclusions**

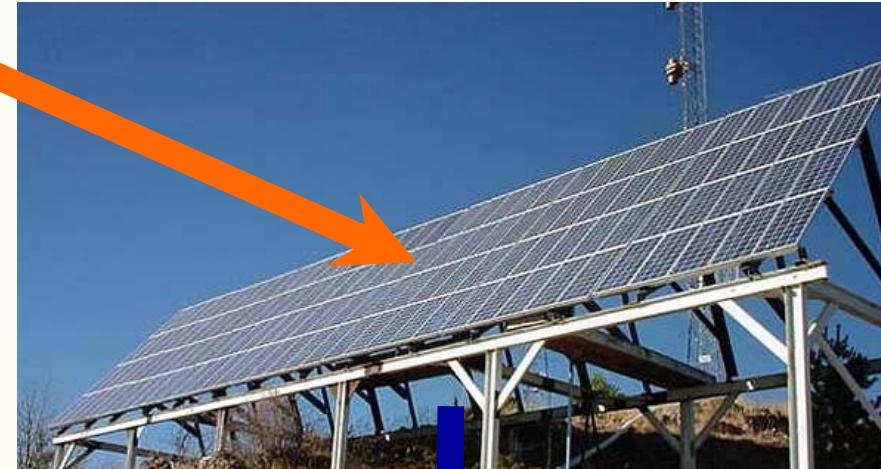


# Introduction

Solar energy



Solar cell (PV modules)



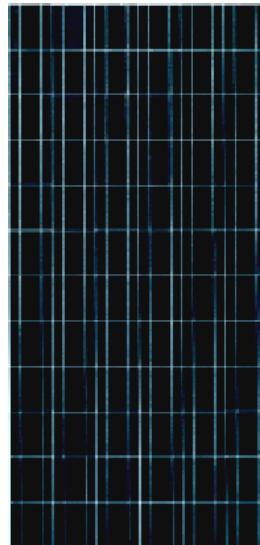
Electrical energy

> 30 % growth in module production per year

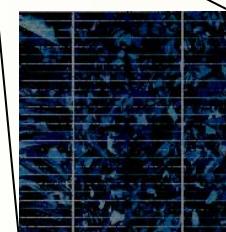


# Introduction

**conventional  
wafer-based solar cells**



cell thickness:  
a few 100 um



**thin-film (TF) solar cells**



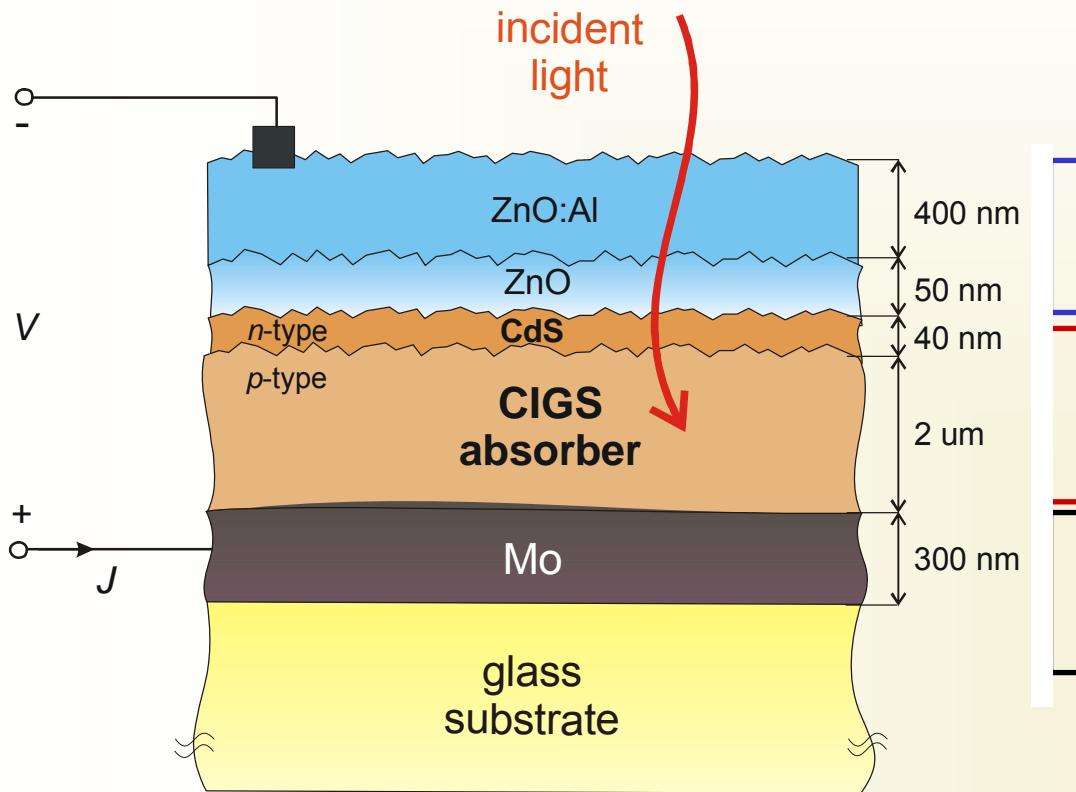
cell thickness:  
a few um or less

- lower material consumption
- low temperature processes
- possibility of being flexible



# Introduction

Cu(Ind,Ga)Se<sub>2</sub> (CIGS) thin-film solar cell:



**Transparent Conductive Oxide (TCO) front contact**

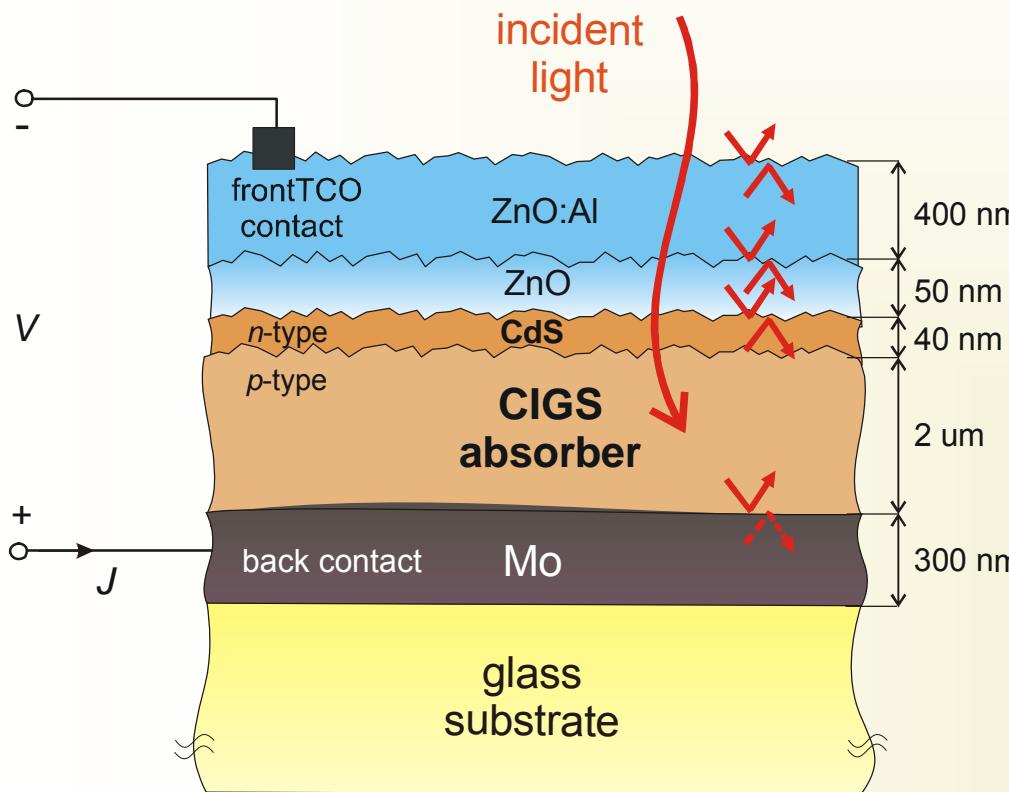
**pn-junction**

**metal contact and substrate**



# Introduction

TF solar cell as an optical system:

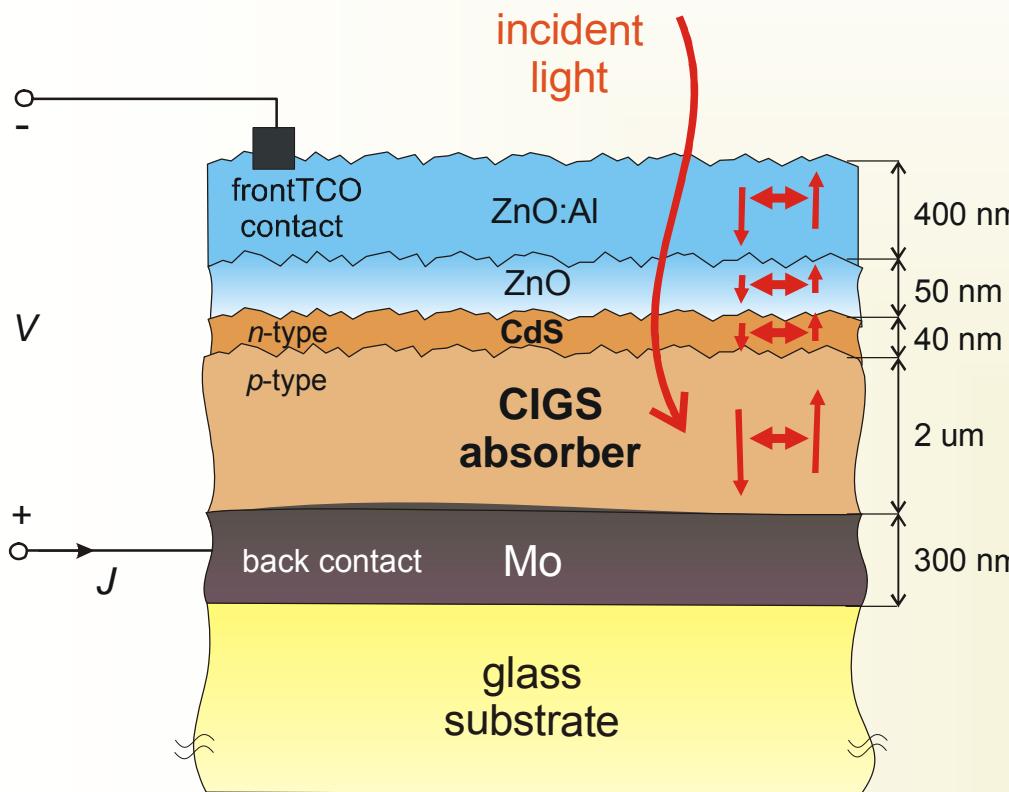


## Optical features:

- multilayer structure
- ↓
- multiple  $R$  and  $T$ !**

# Introduction

TF solar cell as an optical system:



## Optical features:

- multilayer structure
- layers in nm range

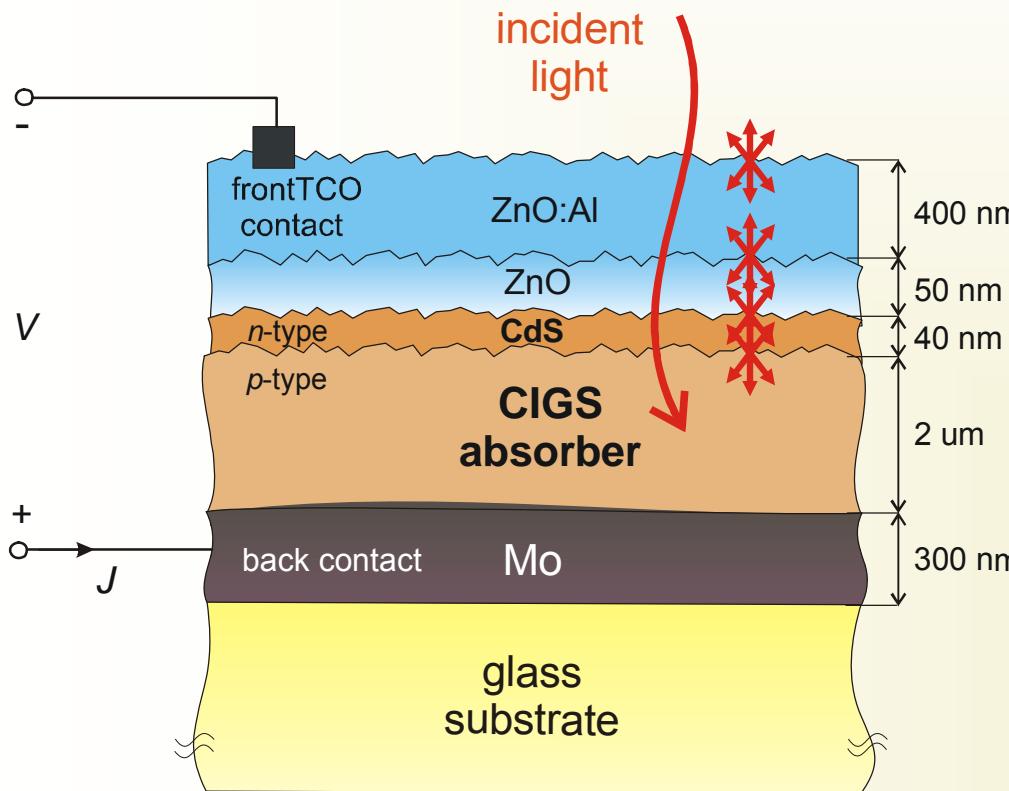


**interferences!**



# Introduction

TF solar cell as an optical system:



## Optical features:

- multilayer structure
- layers in nm range
- textured interfaces

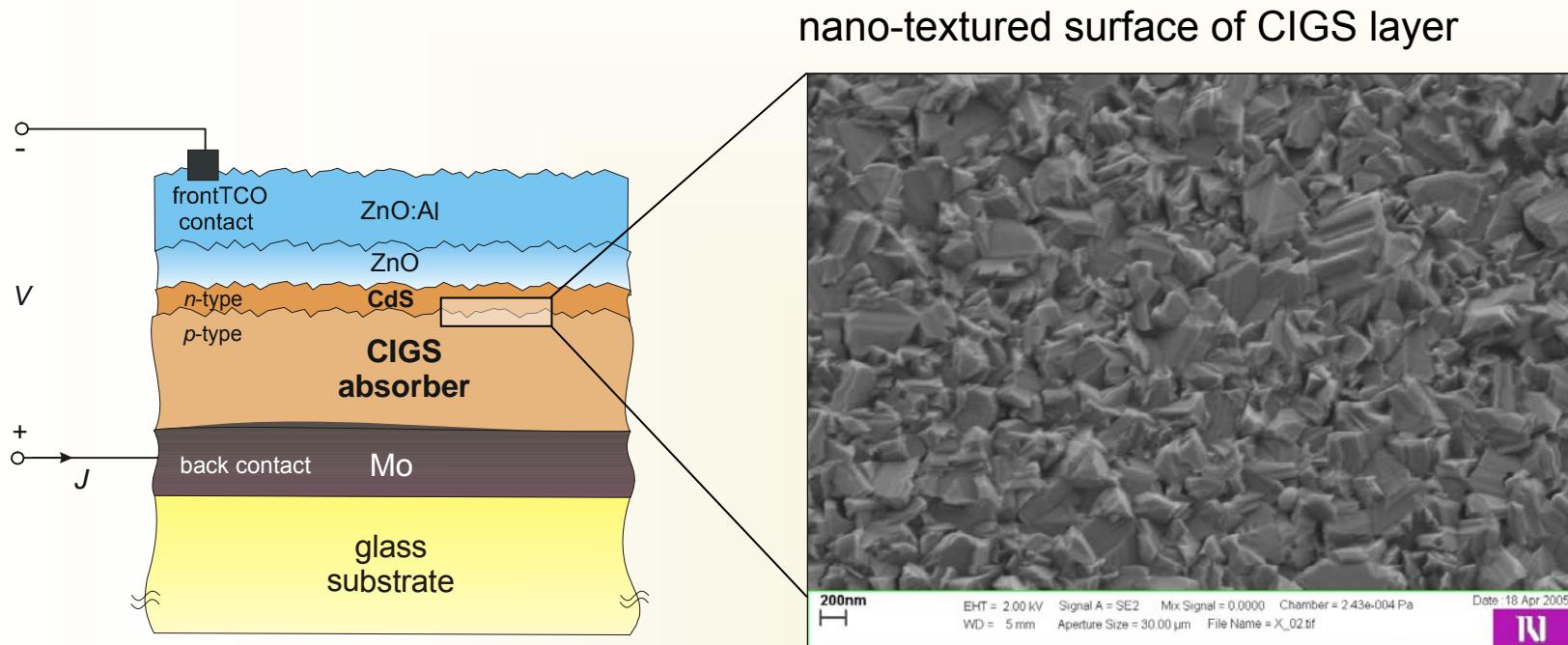


**light scattering!**

# Optical modeling of TF solar cells



# Optical modeling of light scattering

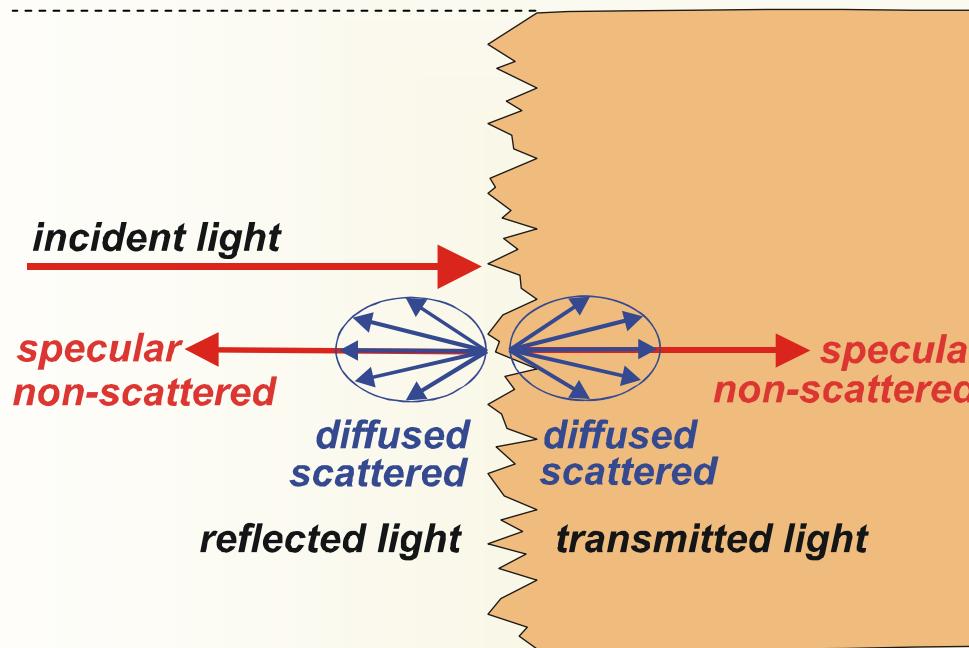




# Optical modeling of light scattering

Light scattering at nano-textured interfaces:

- Specular (non-scattered) light
- Scattered (diffused) light





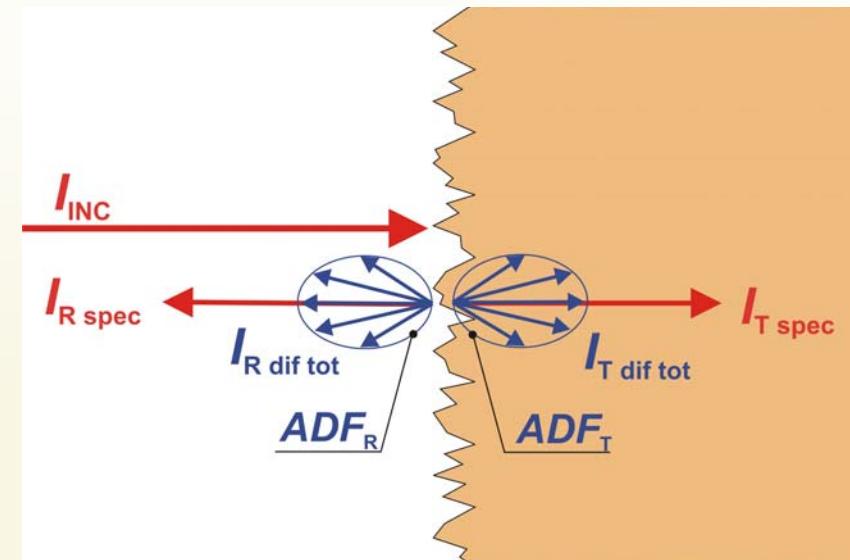
# Optical modeling of light scattering

Descriptive scattering parameters:

## 1. Haze (scattering level)

$$H_R = \frac{I_{R \text{ dif tot}}}{I_{R \text{ dif tot}} + I_{R \text{ spec}}}$$

$$H_T = \frac{I_{T \text{ dif tot}}}{I_{T \text{ dif tot}} + I_{T \text{ spec}}}$$



## 2. Angular distribution functions (directions)

$$ADF_R(\phi_{\text{scatt}})$$

$$ADF_T(\phi_{\text{scatt}})$$



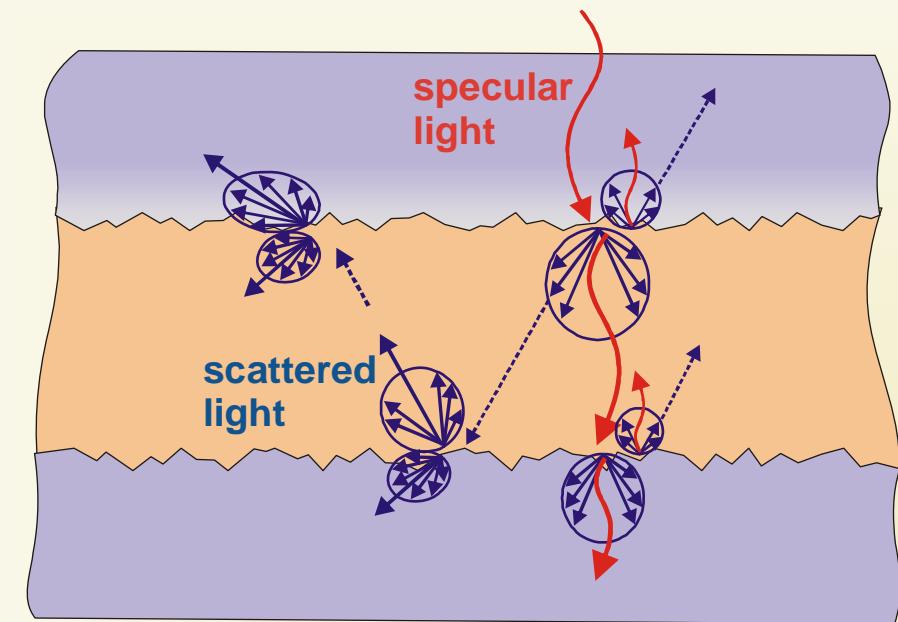
$$I_{T \text{ dif }}(\varphi) = \textcircled{ADF_T(\varphi)} \cdot I_{T \text{ dif tot}}$$

# Optical simulator Sun*Shine*



# Optical simulator SunShine

- 1-D semi-coherent optical model [J. Krc et al., Progress in Photovoltaics 11 (2003) 15.]
- specular light -  
electromagnetic waves (coherent)
- scattered light -  
light rays (incoherent)





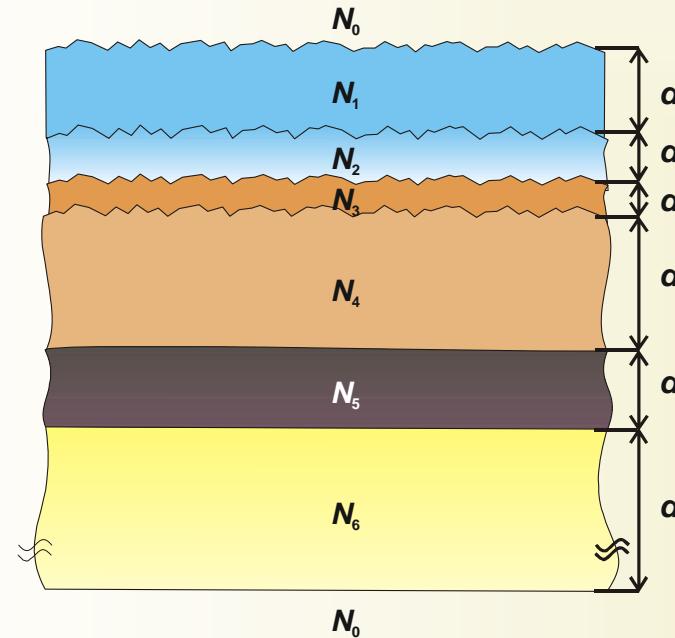
# Optical simulator SunShine

- 1-D semi-coherent optical model [J. Krc et al., Progress in Photovoltaics 11 (2003) 15.]

Main input parameters (structure description):

- Complex refractive indexes and thicknesses of layers

$$N(\lambda) = n(\lambda) - jk(\lambda)$$





# Optical simulator SunShine

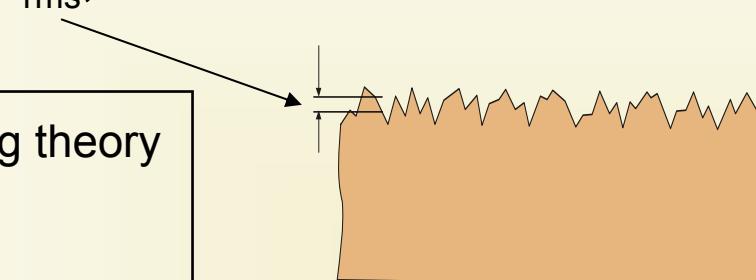
- 1-D semi-coherent optical model [J. Krc et al., Progress in Photovoltaics 11 (2003) 15.]

Main input parameters (structure description):

- Complex refractive indexes and thicknesses of layers
- *Haze* and *ADF* of textured interfaces  
and root-mean-square roughness,  $\sigma_{\text{rms}}$ , of interfaces

Calibrated equations of scalar scattering theory  
(for details refer to our NUSOD paper)

$\sigma_{\text{rms}}, n, \lambda \rightarrow H_R, H_T$  for internal interfaces





# Optical simulator SunShine

- 1-D semi-coherent optical model [J. Krc et al., Progress in Photovoltaics 11 (2003) 15.]

Main input parameters (structure description):

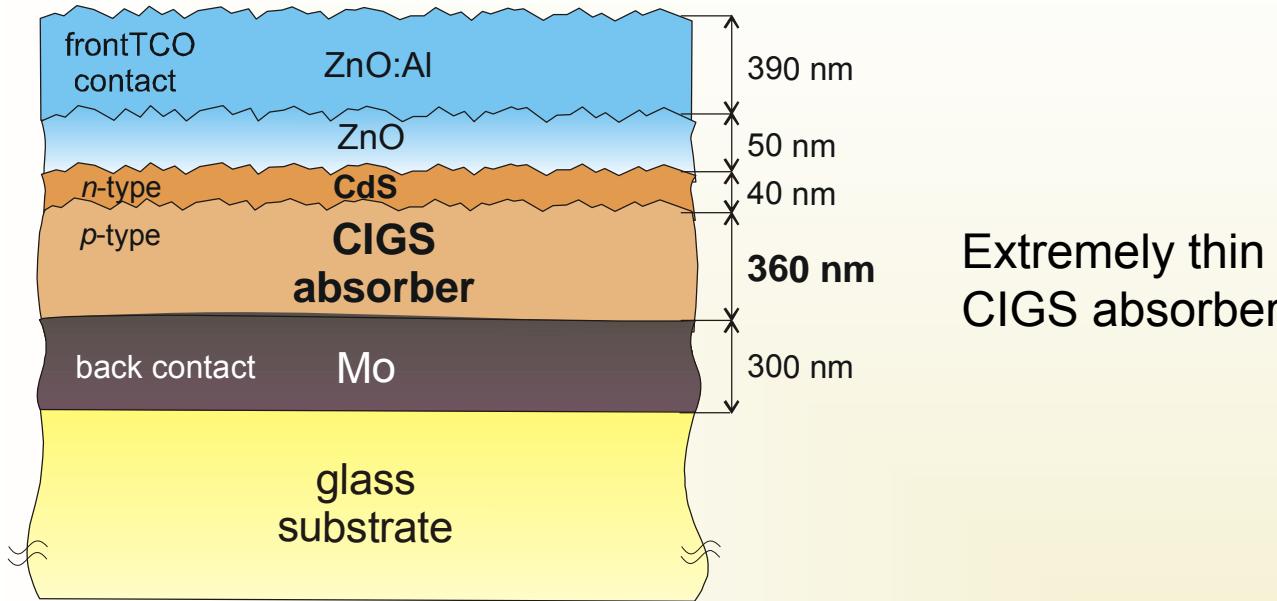
- Complex refractive indexes and thicknesses of layers
- $H$  and  $ADF$  of textured substrates  
and measured root-mean square roughness of interfaces

Main output results:

- Optical reflectance from the structure
- Absorptances in individual layers
- Charge-carrier generation-rate profile

# Simulations

Simulated structure:



- Thinning down CIGS absorber below 1 um  
(lower material consumption, shorter deposition times)
- To analyse and optimise optical and electrical properties

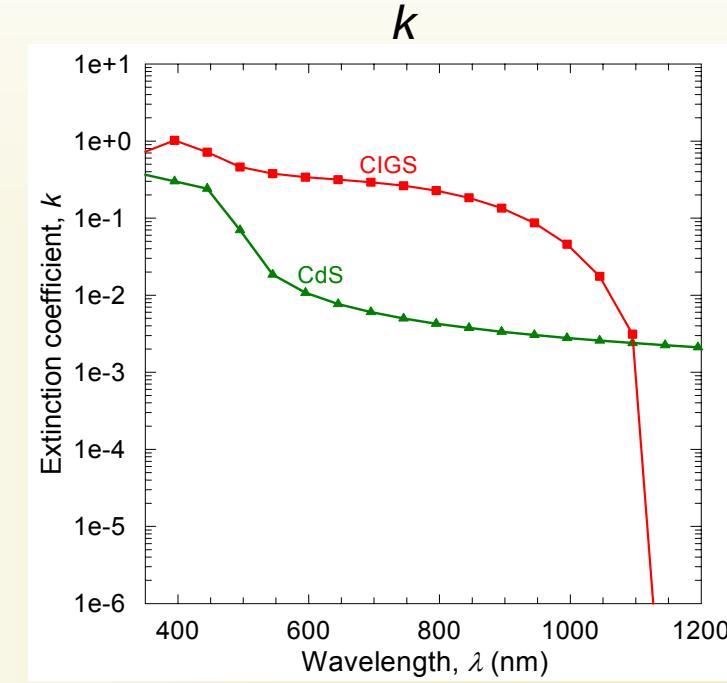
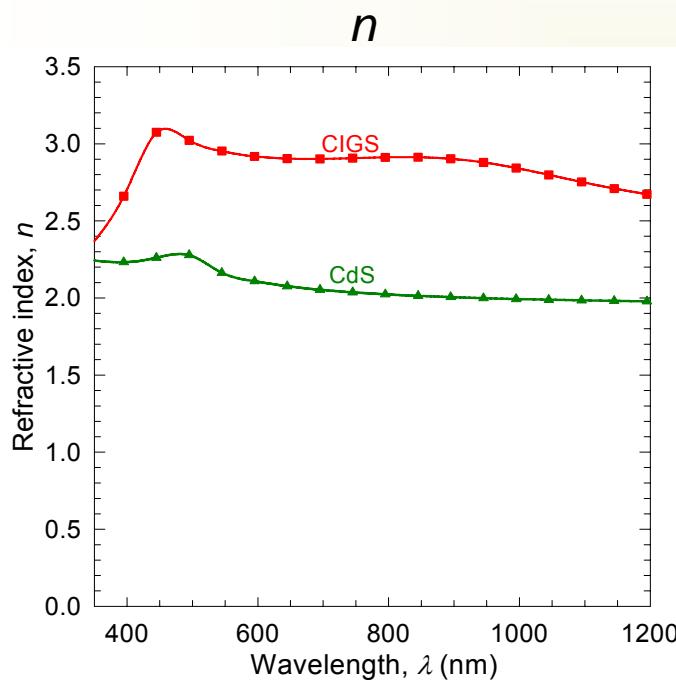
**Numerical modeling&simulation an important tool!**

# Simulations

Included in simulations:

- Experimentally obtained complex refractive indexes of layers

[ O. Lundberg, PhD. Thesis, Uppsala University, 2003]



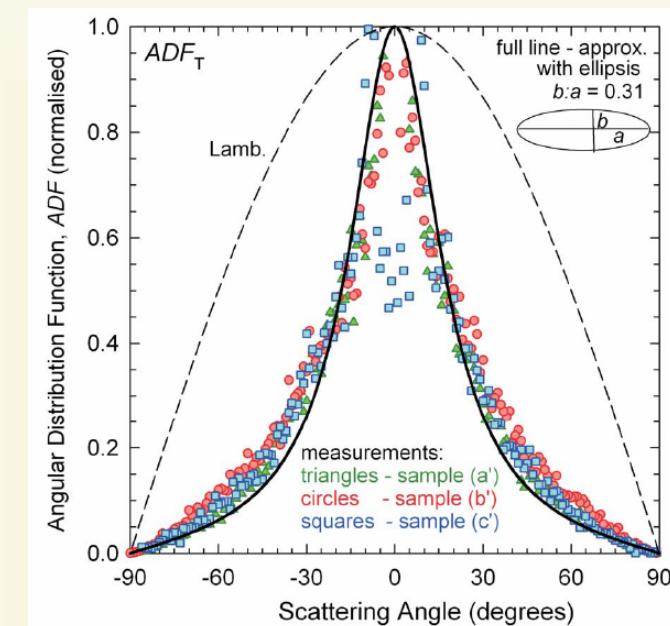
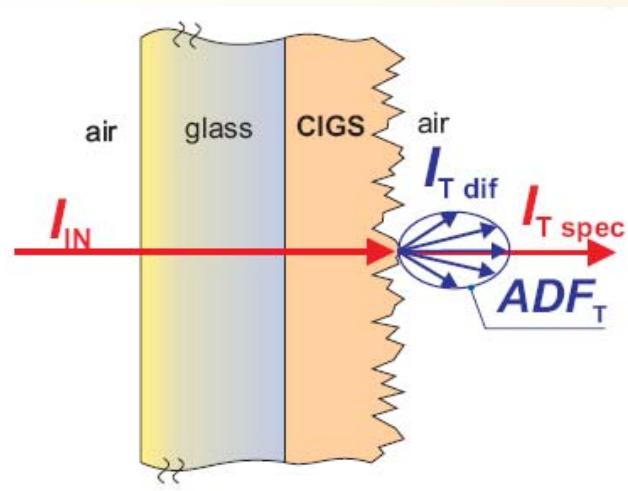


# Simulations

Included in simulations:

- Experimentally obtained complex refractive indexes of layers  
[ O. Lundberg, PhD. Thesis, Uppsala University, 2003]
- Measured  $H$  and  $ADF$  [ J. Krc et al., Proc. of E-PVSEC, Barcelona, 2005, p. 1831.]

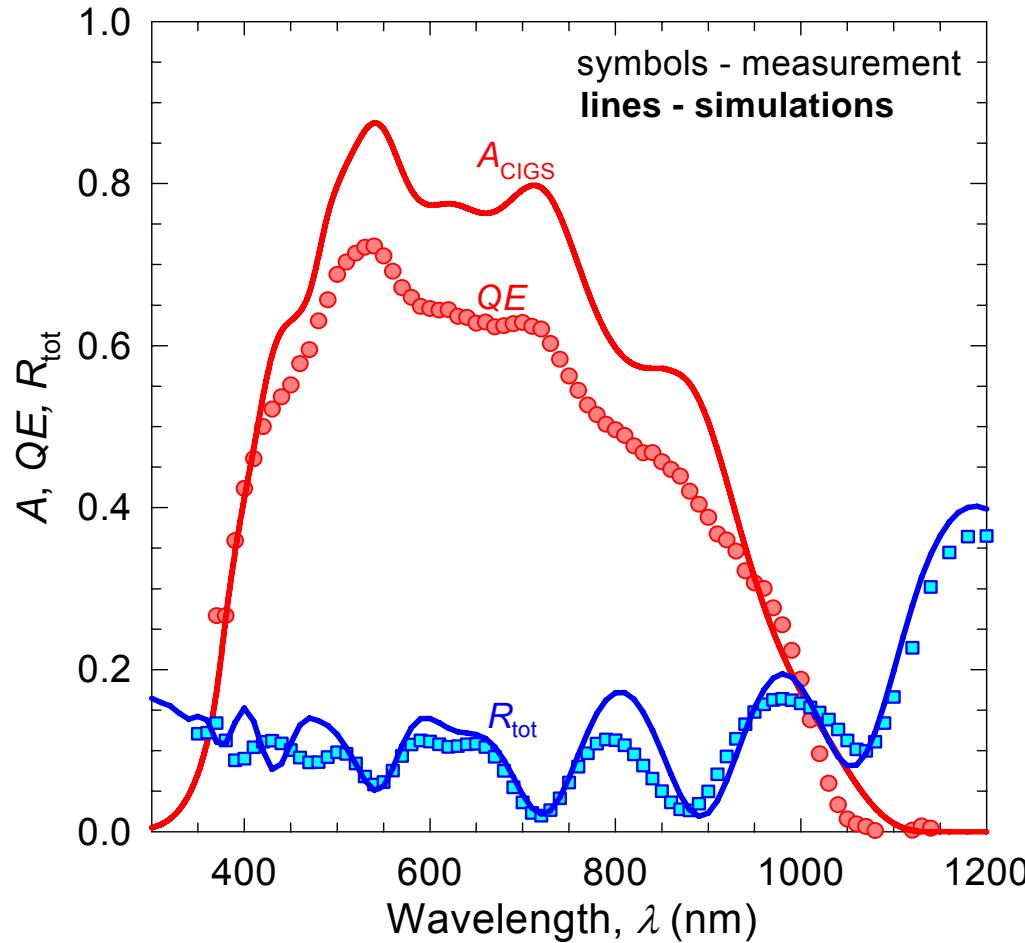
Example of  $ADF_T$  measurement:



# Simulation results

# Simulation results

Total reflectance and quantum efficiency

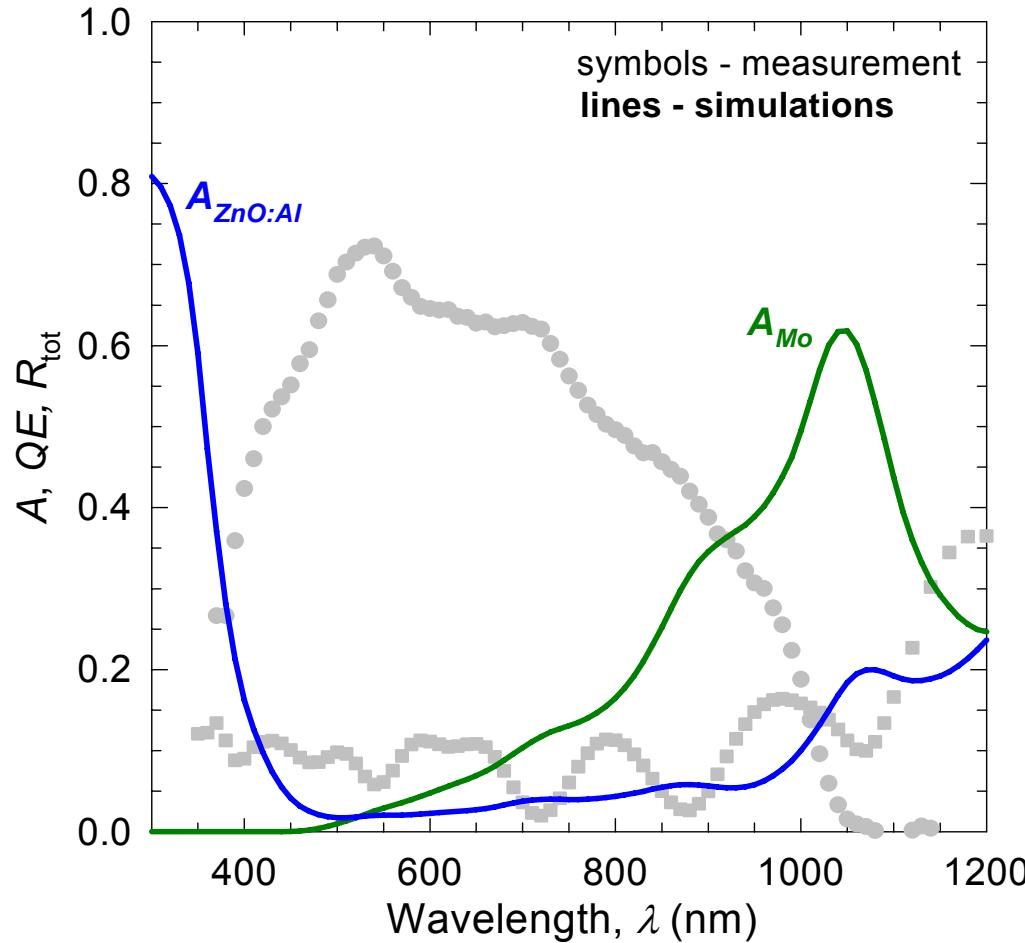


$$A_{\text{CIGS}} \rightarrow QE$$

*if ideal extraction of charge carriers from CIGS*

# Simulation results

## Absorptances in non-active layers

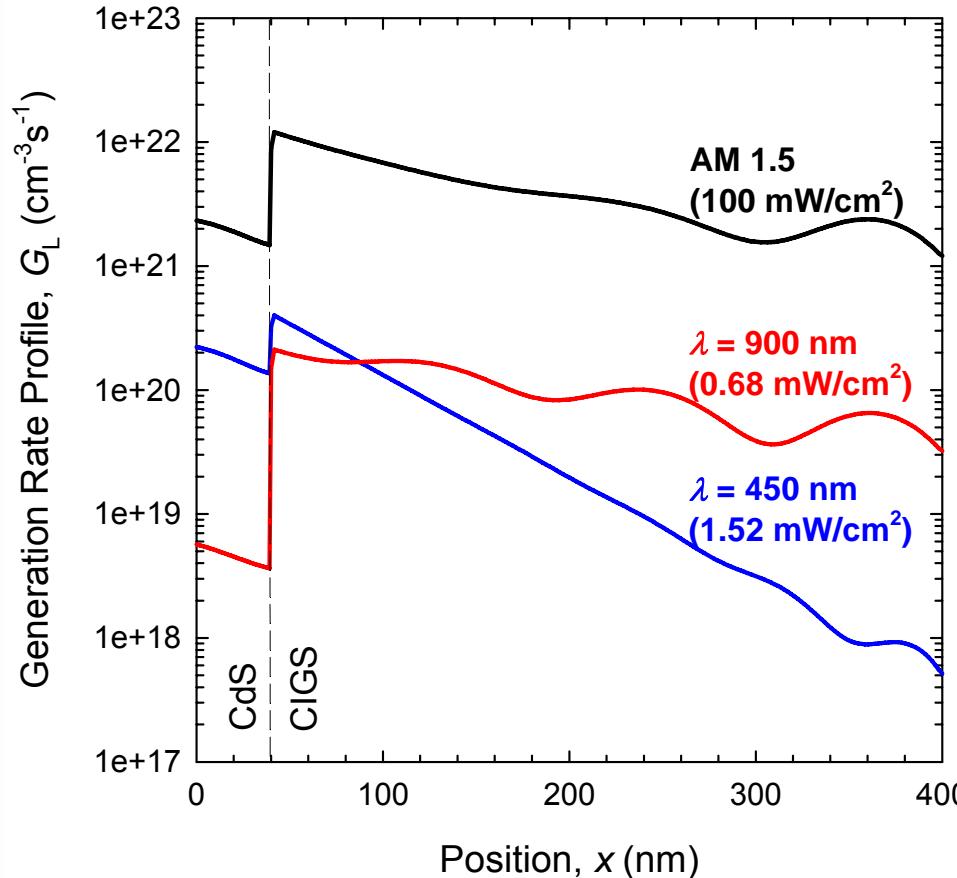


*determination of optical losses in the structure*



# Simulation results

## Charge-carrier generation-rate profile



for further electrical analysis of the structure

# Conclusions

- good agreement in sim. and meas. total reflectance of thin CIGS solar cell
- calibration of the simulator with realistic optical parameters (refractive indexes, scattering and others) is important
- starting point for optical optimisation and electrical analysis of the structure

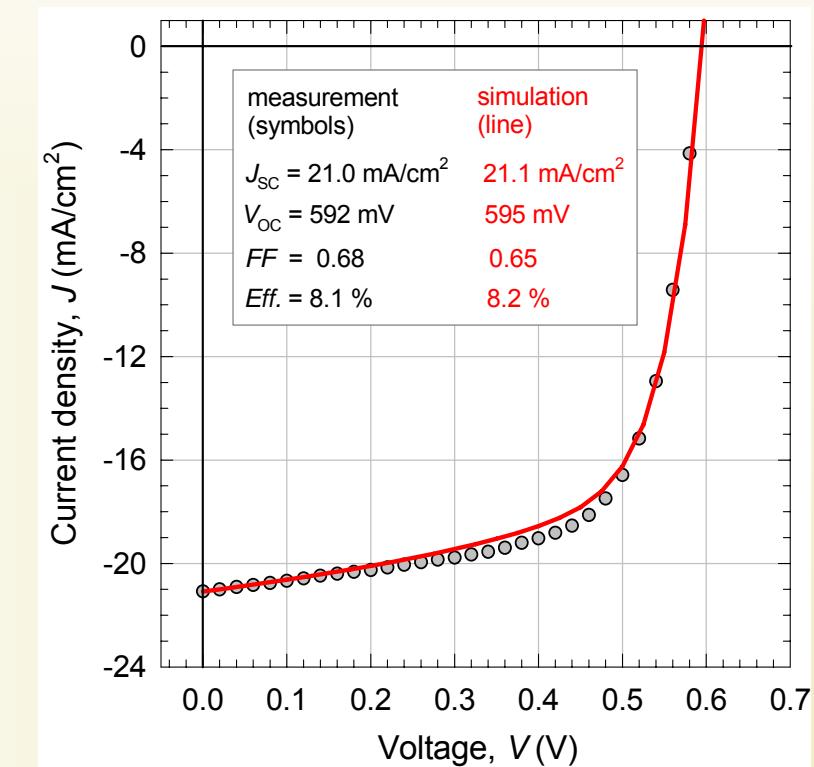
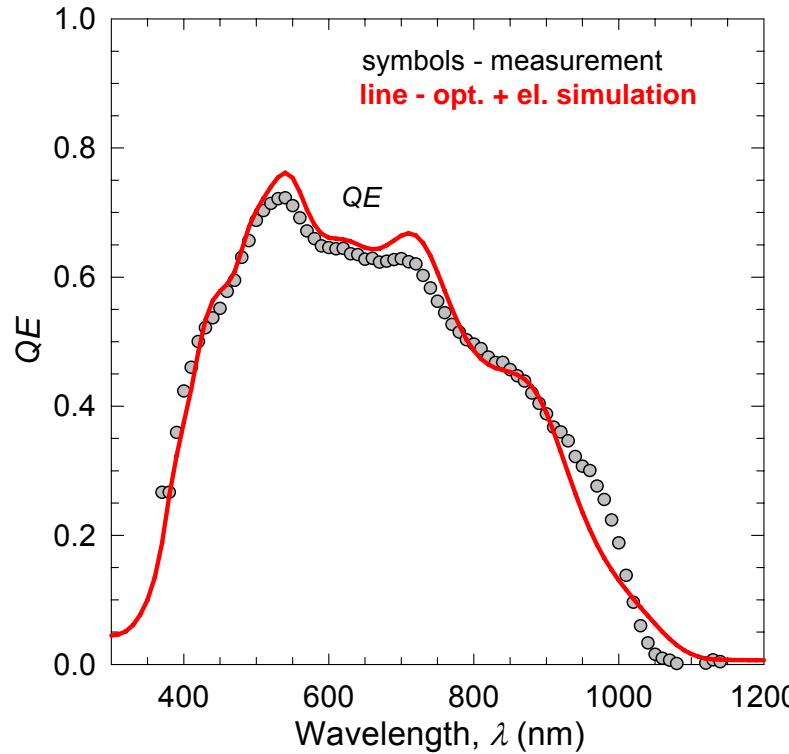


# Further work

*combined optical + electrical analysis of the structure*

**SunShine&Aspin** simulators

*External characteristics and parameters of the solar cell:*



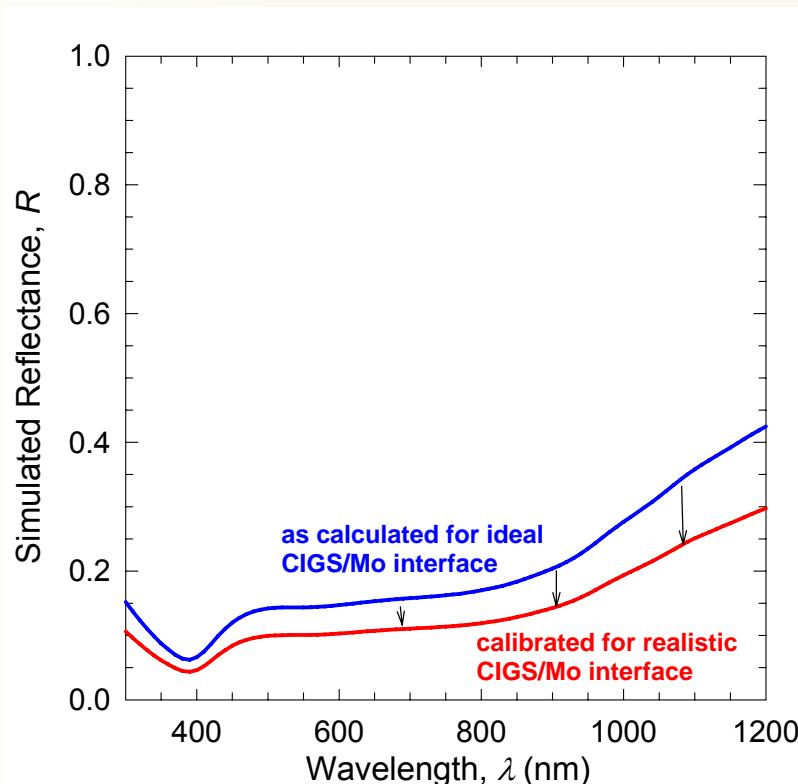
see extended NUSOD paper submitted to OQE



# Simulation

Included in simulations:

- Reduced reflectance of CIGS/Mo interface by 30 %  
(formation of  $\text{MoSe}_2$  interfacial layer) [J. Krc et al., Proc. of E-PVSEC, Barcelona, 2005, p. 1831.]





# Simulation

## Haze of internal interfaces

Modified equations of scalar scattering theory:

$$H_R = 1 - e^{-\left(\frac{4\pi\sigma_{rms} \cdot c_R(\sigma_{rms}, \lambda) n_1 \cos \varphi_{inc}}{\lambda}\right)^2}$$

$c_R, c_T$   
calibration  
functions

$$H_T = 1 - e^{-\left(\frac{4\pi\sigma_{rms} \cdot c_T(\sigma_{rms}, \lambda) |n_1 \cos \varphi_{inc} - n_2 \cos \varphi_{out}|}{\lambda}\right)^{2...3}}$$

*initial values:*

$$c_R = 1$$
$$c_T = 0.5$$

P. Beckmann, A. Spizzichino, Pergamon Press (1963)

C.K. Carniglia, Optical Engineering 18/2 (1979)

M. Zeman et. al. JAP 88 (2000)

J. Krc et al. J. Appl. Phys. 92/2 (2002) 749-755.

J. Krc et al. Thin Solid Films 426/1-2 (2003) 296-304

*basic theory*

*calibration introduced*



# Simulation

Application of the calibrated theory to internal interfaces

